



Mr. Praveen Jain (left), Chief Executive, Vaiseshika is receiving and presenting Welcome Bouquet to Dr. S. E. Hasnain (right), Director, Centre for DNA Fingerprinting and Diagnostics, Hyderabad at Ambala Cantt on 6th December 2005.



Dr. S. E. Hasnain observing a Metallographic specimen through Micro Hardness Tester at Vaiseshika Facility



Mr. Yogesh Kumar (right), Director (LCA), Hindustan Aeronautics Limited, Bangalore is presenting a model of Light Combat Aircraft to Dr. Anil Jain (left), President, Vaiseshika Electron Devices, Ambala Cantt on 25th March 2006.



Dr. Pawan Kapur, Director, Central Scientific Instruments Organization, Chandigarh is inaugurating the Vaiseshika Metrology Laboratory on 25th March 2006.



Dr. Pawan Kapur (extreme right) is discussing a technical point with Dr. Anil Jain (extreme left), President, Vaiseshika on a Micro Hardness Tester at Vaiseshika Facility on 25th March 2006